Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	53	(eliminat$4 or reduc$4 or minimiz$4 or stop$5) near5 (redundant adj2 test$4)	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:29
L2	39	(eliminat$4 or reduc$4 or minimiz$4 or stop$5) adj3 (redundant adj2 test$4)	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:02
L3	16	((eliminat$4 or reduc$4 or minimiz$4 or stop$5) adj3 RIT$2)	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 12:32
L4	8	(((eliminat$4 or reduc$4 or minimiz$4 or stop$5) adj3 RIT$2)) and test$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 12:49
L5	27	(((eliminat$4 or reduc$4 or minimiz$4 or stop$5) near5 RIT$2)) and test$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 12:33
L6	0	(((eliminat$4 or reduc$4 or minimiz$4 or stop$5) near5 RIT$2)) and test$4 and (correlat$4 near3 vector$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 12:34
L7	0	(((eliminat$4 or reduc$4 or minimiz$4 or stop$5) near5 RIT$2)) and (correlat$4 near3 vector$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 12:34
L8	13	(((eliminat$4 or reduc$4 or minimiz$4 or stop$5) near5 RIT$2)) and (vector$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 12:34
L9	12	(((eliminat$4 or reduc$4 or minimiz$4 or stop$5) near5 RIT$2)) and (vector$1) and test$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 12:35
L10	55	(eliminat$4 or reduc$4 or minimiz$4 or stop$5 or analiz$4) adj3 (RIT$2 or (redundant adj2 test$4))	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:08
L11	15	((eliminat$4 or reduc$4 or minimiz$4 or stop$5 or analiz$4) adj3 (RIT$2 or (redundant adj2 test$4))) and vector$1	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:16
L12	10	((eliminat$4 or reduc$4 or minimiz$4 or stop$5 or analiz$4) adj3 (RIT$2 or (redundant adj2 test$4))) and ((IC near2 test$3) or (chip$1 near2 test$4))	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 12:39
L13	11	((eliminat$4 or reduc$4 or minimiz$4 or stop$5 or analiz$4) adj3 (RIT$2 or (redundant adj2 test$4))) and ((IC$1 near2 test$3) or (chip$1 near2 test$4))	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 12:40

L14	17	((eliminat$4 or reduc$4 or minimiz$4 or stop$5 or analiz$4) adj3 (RIT$2 or (redundant adj2 test$4))) and ((IC$1 near2 test$4) or (chip$1 near2 test$4) or ((integrated adj2 circuit$1) near2 test$4))	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 12:43
L15	0	Kang-w.$.in.	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:04
L16	792	Kang-w$.in.	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:05
L17	0	Kang-wu.in.	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:05
L18	4	wu-Kang.in.	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:07
L19	4	stirrat-su$.in.	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:07
L20	49	eliminat$4 near3 ((redundant adj2 test$1) or (repeat$4 adj2 test$1))	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:18
L21	29	eliminat$4 adj2 ((redundant adj2 test$1) or (repeat$4 adj2 test$1))	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:25
L22	1	(test adj2 sequence$1) same (correlation adj2 vector$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:27
L23	786	(correlation adj2 vector$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:26
L24	7	(correlation adj2 vector$1) near4 test$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:26
L25	5	(test adj2 sequence$1) and (correlation adj2 vector$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:28
L26	72	(eliminat$4 or reduc$4 or minimiz$4 or stop$5) near10 (redundant adj2 test$4)	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:29
L27	24380	((test$4 near2 IC$2) or (test$3 near2 chip$1) or (test$4 near3 dice$1))	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:40
L28	21	((test$4 near2 IC$2) or (test$3 near2 chip$1) or (test$4 near3 dice$1)) and l26	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:34

L29	0	((test$4 near2 IC$2) or (test$3 near2 chip$1) or (test$4 near3 dice$1)) and ("binary-valued L-dimentional vectoR")	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:42
L30	1530	((test$4 near2 IC$2) or (test$3 near2 chip$1) or (test$4 near3 dice$1)) and (sequence$1 near3 test$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:42
L31	596	((test$4 near2 IC$2) or (test$3 near2 chip$1) or (test$4 near3 dice$1)) and (sequence$1 near3 test$1) and vector$1	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:43
L32	176	((test$4 near2 IC$2) or (test$3 near2 chip$1) or (test$4 near3 dice$1)) and (sequence$1 near3 test$1) and vector$1 and optimiz$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:44
L33	13	((test$4 near2 IC$2) or (test$3 near2 chip$1) or (test$4 near3 dice$1)) and (sequence$1 near3 test$1) and (product near5 vector$1) and optimiz$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:45
L34	13	((test$4 near2 IC) or (test$3 near2 chip$1) or (test$4 near3 dice$1)) and (sequence$1 near3 test$1) and (product near5 vector$1) and optimiz$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:46
L35	170	((test$4 near2 IC) or (test$3 near2 chip$1) or (test$4 near3 dice$1)) and (sequence$1 near3 test$1) and (vector$1) and optimiz$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:46
L36	195	((test$4 near2 IC) or (test$3 near2 chip$1) or (test$4 near (integrated adj2 circuit$1))) and (sequence$1 near3 test$1) and (vector$1) and optimiz$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 13:49
L37	5	((test$4 near2 IC) or (test$3 near2 chip$1) or (test$4 near (integrated adj2 circuit$1))) same (sequence$1 near3 test$1) same optimiz$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 14:11
L38	5	detect$4 adj4 (redundant adj2 test)	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 14:12
L39	21	(detect$4 or eliminat$4 or check$4 or minimiz$4 or reduc44) adj4 (redundant adj2 test)	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 14:13
L40	24	(detect$4 or eliminat$4 or check$4 or minimiz$4 or reduc$4) adj4 (redundant adj2 test)	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/12/02 14:13

| L41 | 21 | (detect$4 or eliminat$4 or check$4 or minimiz$4 or reduc$4) adj2 (redundant adj2 test) | USPAT; EPO; JPO; DERWENT | OR | OFF | 2004/12/02 14:14 |